

**Amendments to the Abstract**

Replace the abstract with the following replacement abstract:

~~The present invention relates to a~~ A process for the automatic control of the thickness of extruded film ~~(8)~~. ~~The purpose of the invention is to lower~~ lowers the deviations in the thickness of the film more quickly after the start of the extrusion process.

The process ~~involves~~ includes the measurement of the thickness profile of the film ~~(8)~~ just extruded by means of a thickness-measuring probe ~~(12)~~. The thickness-measuring probe ~~(12)~~ is moved along the surface of the film substantially perpendicular ~~(x)~~ to the conveying direction ~~(z)~~ of the extruded film ~~(8)~~. The thickness-measuring probe ~~(12)~~ records a thickness profile ~~(P)~~ of the film ~~(8)~~ for each measuring cycle ~~(MZ)~~ at least over parts of the expansion of the film ~~(8)~~ perpendicular ~~(x)~~ to its conveying direction ~~(z)~~.

~~The process pursuant to the present invention is characterized by the fact that while~~ While providing the statistical values in relation to the older measured values, the latest measured value(s) values during a predetermined time-frame at the start of the extrusion process are more heavily weighted by ~~the a~~ computer ~~(14)~~ than those measured during the normal operation.

~~(Figure 1)~~

For the examiner's convenience, a clean text version of the replacement abstract (139 words) is presented below:

A process for the automatic control of the thickness of extruded film lowers the deviations in the thickness of the film more quickly after the start of the extrusion process. The process includes the measurement of the thickness profile of the film just extruded by means of a thickness-measuring probe. The thickness-measuring probe is moved along the surface of the film substantially perpendicular to the conveying direction of the extruded film. The thickness-measuring probe records a thickness profile of the film for each measuring cycle at least over parts of the expansion of the film perpendicular to its conveying direction. While providing statistical values in relation to older measured values, the latest measured values during a predetermined time-frame at the start of the extrusion process are more heavily weighted by a computer than those measured during the normal operation.